

## 82S291A 16K-Bit TTL Bipolar PROM

### Military Bipolar Memory Products

### Product Specification

#### DESCRIPTION

The 82S291A is field programmable, which means that custom patterns are immediately available by following the Signetics Generic II fusing procedure. The 82S291A is supplied with all outputs at a logical High. Outputs are programmed to a logic Low level at any specified address by fusing the vertical junction matrix.

This device includes on-chip decoding and 3 chip enable inputs for ease of memory expansion. It features 3-State outputs for optimization of word expansion in bused organizations.

#### FEATURES

- Address access time: 35ns max
- Input loading:  $-250\mu\text{A}$  max
- Three chip enable inputs
- On-chip address decoding
- No separate fusing pins
- Unprogrammed outputs are High level
- Fully TTL compatible
- Outputs: 3-State

#### APPLICATIONS

- Sequential controllers
- Microprogramming
- Hardwired algorithms
- Control store
- Random logic
- Code conversion
- Prototyping/volume production

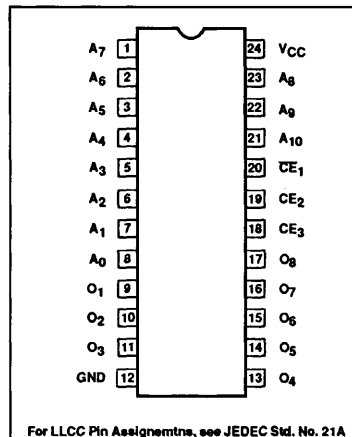
#### ORDERING INFORMATION

DESCRIPTION	ORDER CODE
24-pin Ceramic Dual-In-Line 300mil-wide	82S291A/BLA

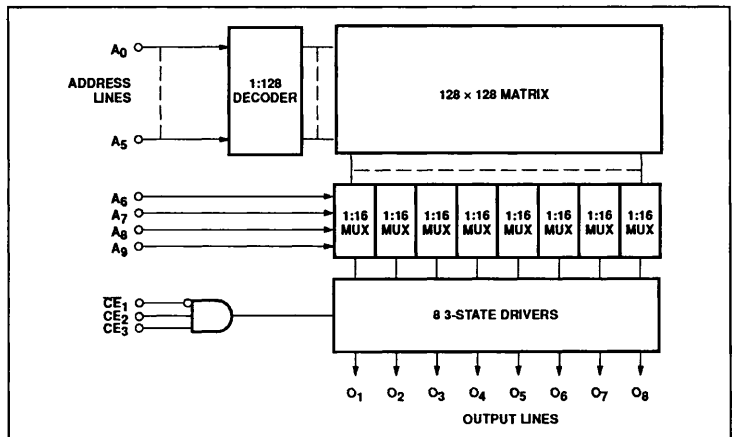
#### ABSOLUTE MAXIMUM RATINGS

SYMBOL	PARAMETER	RATING	UNIT
$V_{CC}$	Supply voltage	+7	$V_{DC}$
$V_I$	Input voltage	+5.5	$V_{DC}$
$V_O$	Output voltage Off-State	+5.5	$V_{DC}$
$T_{STG}$	Storage temperature range	-65 to +150	$^{\circ}\text{C}$

#### PIN CONFIGURATION



#### BLOCK DIAGRAM



# 16K-Bit TTL Bipolar PROM (2048 × 8)

82S291A

## RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		Min	Nom	Max	
V <sub>CC</sub>	Supply voltage	4.5	5.0	5.5	V
V <sub>IH</sub> <sup>7</sup>	High-level input voltage	2.0			V
V <sub>IL</sub> <sup>7</sup>	Low-level input voltage			0.8	V
I <sub>IK</sub>	Input clamp current			-18	mA
I <sub>OH</sub>	High-level output current			-2	mA
I <sub>OL</sub>	Low-level output current			16	mA
T <sub>A</sub>	Operating free-air temperature range	-55		+125	°C

## DC ELECTRICAL CHARACTERISTICS -55°C ≤ T<sub>A</sub> ≤ +125°C, 4.5V ≤ V<sub>CC</sub> ≤ 5.5V

SYMBOL	PARAMETER	TEST CONDITIONS <sup>1,2</sup>	LIMITS			UNIT
			Min	Typ <sup>5</sup>	Max	
V <sub>IK</sub>	Input clamp voltage	V <sub>CC</sub> = Min, I <sub>I</sub> = Max		-0.8	-1.2	V
V <sub>OL</sub>	Output Low-level current	$\overline{CE}_1$ = Low, CE <sub>2,3</sub> = High, V <sub>CC</sub> = Min, I <sub>OL</sub> = Max			0.5	V
V <sub>OH</sub>	Output High-level current	$\overline{CE}_1$ = Low, CE <sub>2,3</sub> = High, V <sub>CC</sub> = Min, I <sub>OH</sub> = Max	2.4			V
I <sub>IL</sub>	Input Low-level current	V <sub>CC</sub> = Max, V <sub>I</sub> = 0.45V			-250	μA
I <sub>IH</sub>	Input High-level current	V <sub>CC</sub> = Max, V <sub>I</sub> = 5.5V			40	μA
I <sub>OLZ</sub>	Off-State output current Low-State	V <sub>CC</sub> = Max, $\overline{CE}_1$ = High, CE <sub>2,3</sub> = Low, V <sub>O</sub> = 0.4			-40	μA
I <sub>OHZ</sub>	Off-State output current High-State	$\overline{CE}_1$ = High, CE <sub>2,3</sub> = Low, V <sub>O</sub> = 5.5, V <sub>CC</sub> = Max			40	μA
I <sub>OS</sub>	Output short circuit current <sup>3</sup>	$\overline{CE}_1$ = Low, CE <sub>2,3</sub> = High, V <sub>CC</sub> = Max, V <sub>O</sub> = 0V	-15		-85	mA
I <sub>CC</sub>	Supply current <sup>8</sup>	$\overline{CE}_1$ = High, CE <sub>2,3</sub> = Low, V <sub>CC</sub> = 5.5V		130	185	mA
C <sub>IN</sub>	Input capacitance <sup>6</sup>	$\overline{CE}_1$ = High, CE <sub>2,3</sub> = Low, V <sub>CC</sub> = 5.0V V <sub>I</sub> = 2.0V		5	10	pF
C <sub>OUT</sub>	Output capacitance <sup>6</sup>	V <sub>O</sub> = 2.0V		8	13	pF

## AC ELECTRICAL CHARACTERISTICS -55°C ≤ T<sub>A</sub> ≤ +125°C, 4.5V ≤ V<sub>CC</sub> ≤ 5.5V

SYMBOL	PARAMETER	TO	FROM	LIMITS			UNIT
				Min	Typ <sup>5</sup>	Max	
t <sub>AA</sub>	Access time <sup>4</sup>	Output	Address		15	35	ns
t <sub>CE</sub>	Access time <sup>4</sup>	Output	Chip Enable		10	20	ns
t <sub>CD</sub>	Disable time	Output	Chip Disable		10	20	ns

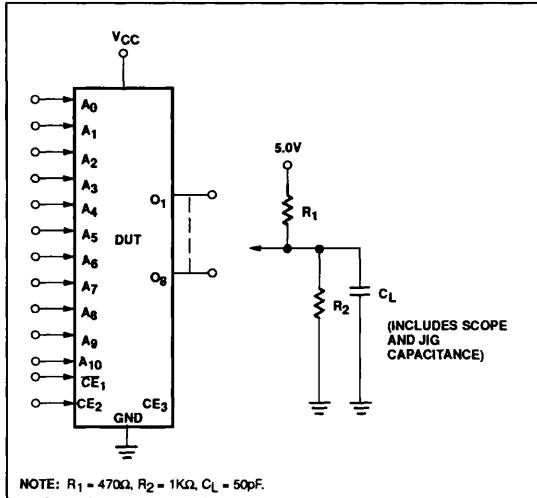
### NOTES:

1. Positive current is defined as into the terminal referenced.
2. All voltages with respect to network ground.
3. Duration of short circuit should not exceed 1 second.
4. Tested at an address cycle time of 1μs.
5. Typical values are at V<sub>CC</sub> = 5V, T<sub>A</sub> = +25°C.
6. Guaranteed, but not tested.
7. Measured with one output switching from a logic "1" to a logic "0". These are absolute voltages with respect to device ground pin and include all overshoots due to system and/or tester noise. Testing of these values requires special equipment.
8. Measured with all inputs grounded and all outputs open.

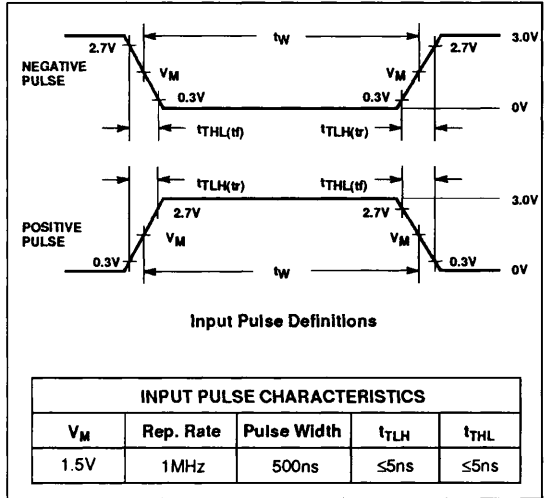
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## TEST LOAD CIRCUITS



## VOLTAGE WAVEFORMS



## TIMING DIAGRAMS

